Title (en)

Contour measurement device and method for measuring a contour

Title (de)

Konturmesseinrichtung und Verfahren zur Messung einer Kontur

Title (fr)

Dispositif de mesure de contours et procédé pour mesurer un contour

Publication

EP 1216766 A3 20040506 (DE)

Application

EP 01128696 A 20011201

Priority

DE 10063773 A 20001221

Abstract (en)

[origin: EP1216766A2] Contour measuring device (12) comprises a number of distance sensors (20) for determining the distance of the device from the surface of the roller; and a measuring system (30) for determining the position of each sensor relative to a fixed point of the roll stand (2). An Independent claim is also included for a process for measuring the contour of a roller arranged in a roll stand. Preferred Features: The sensors are formed as fluidized current sensors. The measuring system is an optical system having a source for emitting laser light.

IPC 1-7

B21B 38/12

IPC 8 full level

B21B 38/12 (2006.01)

CPC (source: EP)

B21B 38/12 (2013.01)

Citation (search report)

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- [XY] PATENT ABSTRACTS OF JAPAN vol. 007, no. 192 (P - 218) 23 August 1983 (1983-08-23)
- [XA] PATENT ABSTRACTS OF JAPAN vol. 007, no. 192 (P - 218) 23 August 1983 (1983-08-23)

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DOCDB simple family (publication)

EP 1216766 A2 20020626; **EP 1216766 A3 20040506**; DE 10063773 A1 20020627

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EP 01128696 A 20011201; DE 10063773 A 20001221